

<b>Notice of References Cited</b>		Application/Control No. 10/635,122	Applicant(s)/Patent Under Reexamination HWANG ET AL.	
		Examiner Laura S. Weiner	Art Unit 1745	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,977,277	11-1999	Yokoyama et al.	526/314
*	B	US-6,933,080	08-2005	Lee et al.	429/317
	C	US-			
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	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	JP 2000-319531	11-2000	Japan	Yamamoto et al.	
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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